


<b>Search Notes</b>  	<b>Application/Control No.</b>  10636140	<b>Applicant(s)/Patent Under Reexamination</b>  YAMAGISHI, JUNICHI
	<b>Examiner</b>  Chawan, Sheela C	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	115,118, 190,124,224,116,	1/18/07	SCC
713	186,184,170,	"	"
235	380,382.5,	"	"
463	25, 29	"	"
340	5.67, 5.53, 5.83, 5.52, 5.8, 5.81, 5.83	"	"
902	3,	"	"
283	904, 77,	"	"
705	1, 26, 42, 67	"	"
702	127	"	"
382	115	6/23/07	SCC
340	5.53	"	"
SEARCH UP-DATE.		"	"

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, US-PGPUB,USPAT,EPO,JPO,DERWENT, IBM-TDB.	1/18/07	SCC
INVENTOR NAME SEARCH.	"	"
SEARCH AND OTHER DATABASES , SEE THE SEARCH HISTORY PRINT OUT AND UP DATE THE SEARCH.	6/23/07	SCC
382/115.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.	"	"
340/5.53 "	"	"
INTERFERENCE SEARCH , SEE SEARCH HISTORY PRINT OUT.	"	"
SEARCH IEEE OR INSPEC DATA BASE4.	"	"
ABOVE SEARCH UP-DATE.	"	"

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	115	6/23/07	SCC
340	5.53	"	"